

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: 2813

Examiner: Jack S. J. CHEN

INFORMATION DISCLOSURE

STATEMENT WITH CERTIFICATION

In-Re PATENT APPLICATION Of:

Applicants:

Toshikazu MIZUKOSHI

Serial No.:

10/635,506

Filed:

August 7, 2003

For:

METHOD OF FABRICATING A

SEMICONDUCTOR DEVICE HAVING

TRENCHES

Docket No.:

OKI 361

April 9, 2004

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

This is an information disclosure statement submitted in compliance with the timing requirements of 37 C.F.R. §1.97 (b)(3), i.e., prior to a First Office Action on the Merits.

Attached are copies of two Japanese publications together with their English-language Abstracts. These documents were all cited in a counterpart application. Also listed for consideration are two U.S. patents corresponding to the two Japanese publications. Any relevance of the Japanese publications can be gleaned from the attached English-language Abstracts or from the listed corresponding U.S. patents. The documents are listed on the attached Form PTO-1449.

It is hereby certified that each item of information contained in the Information

Disclosure Statement was first cited in a communication from a foreign patent office in a

counterpart foreign application not more than three months prior to the filing of this Information

Disclosure Statement.

Consideration of the listed documents is respectfully requested.

Respectfully, submitted

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FEE ENCLOSED:\$ Please charge any further fee to our Deposit Account No. 18-0002

RHB:crh

INFORMATION DISCLOSURE STATEMENT APR 0 9 2004 U.S. PATEN				Atty. Docket: OKI 361	Application No.: 10/635,506		
				Applicant: Toshikazu MIZUKOSHI			
				Filing Date: August 7, 2003	Group Art Unit: 2813		
		BADEMAR	U.S. PATEN	T DOCUMENTS			
Examiner Initial		Document Number	Date	Name	Class	Sub- Class	Filing Date
	AA	US 6, 599,811 E	1 07/29/03	Kazama et al.			
	AB	US 6,566,224 B	1 05/20/03	Chang et al.			
	AC						
	AD						
	AE						
	AF						
	AG						
	АН						
		T	FOREIGN PAT	ENT DOCUMENTS			
		Document Number	Date	Country	Class	Sub- Class	Trans- lation
	AI	JP 11-233614	08/27/99	Japan			Abstract
	AJ	JP 11-097523	04/09/99	Japan .			Abstract
	AK						
	AL						
	AM						
		OTHER (In	cluding Author, T	itle, Date, Pertiner	nt Pages, etc.)	·	1.
	AN						
	AO						
Examiner					Date Considered		
EXAMINER through cital Applicant.	R: Initia	al if reference co not in conforma	nsidered, whether once and not conside	r not citation is in con red. Include copy of	formance with MP this form with next	EP 609; d communi	fraw line ication to